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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF:

Fuyuhiko INOUE, et al.

SERIAL NUMBER: 10/080,537

FILED: February 25, 2002

FOR: WAVEFRONT ABERRATION MEASURING METHOD AND UNIT,
EXPOSURE APPARATUS, DEVICE MANUFACTURING METHOD,
AND DEVICE

STATUS REQUEST

Honorable Commissioner of Patents & Trademarks
Alexandria, Virginia 22313

SIR:

The Patent Office is respectfully requested to advise the undersigned of the approximate date a first Official Action will be issued in this Application.

A duplicate of this request and a prepaid return envelope are enclosed for your convenience.

Respectfully submitted,

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